US00D764332S

(12) **United States Design Patent**
Teranishi et al.

(10) **Patent No.:** **US D764,332 S**
(45) **Date of Patent:** ** **Aug. 23, 2016**

---

(54) **PROBE PIN**

(71) Applicant: **OMRON Corporation**, Kyoto-shi, Kyoto (JP)

(72) Inventors: **Hirotada Teranishi**, Osaka (JP); **Takahiro Sakai**, Moriyama (JP)

(73) Assignee: **OMRON Corporation**, Kyoto (JP)

(**) Term: **15 Years**

(21) Appl. No.: **29/528,960**

(22) Filed: **Jun. 2, 2015**

(30) **Foreign Application Priority Data**

Dec. 4, 2014 (JP) 2014-027122

(51) **LOC (10) Cl.** **10-04**
(52) **U.S. Cl.**
USPC **D10/80**
(58) **Field of Classification Search**
USPC D10/78, 80; D13/133, 154
CPC G01R 1/067; G01R 1/06705; G01R 1/06711; G01R 1/06716; G01R 1/06722; G01R 1/06727; G01R 1/06733; G01R 1/06738; G01R 1/06744; G01R 1/0675; G01R 1/06766; G01R 1/06772; G01R 1/06777; G01R 1/06783; G01R 1/0678
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D133,267	S *	8/1942	Burt	439/883
D229,184	S *	11/1973	Brown et al.	D10/103
D325,564	S *	4/1992	Lemke	D13/154
D507,197	S *	7/2005	Sun	D10/72
D662,895	S *	7/2012	Kimura	D13/154
D665,744	S *	8/2012	Yamauchi	D13/133
D665,745	S *	8/2012	Yamauchi	D13/133
8,366,496	B2 *	2/2013	Hsu	G01R 1/0466 439/66
8,460,010	B2 *	6/2013	Kimura	G01R 1/06722 439/66
8,669,774	B2 *	3/2014	Kato	G01R 1/06722 324/755.01
8,808,038	B2 *	8/2014	Hwang	G01R 1/06722 439/66
9,130,290	B2 *	9/2015	Sakai	H01R 13/2428

(Continued)

FOREIGN PATENT DOCUMENTS

KR	30-0653160	7/2012
KR	300735080	3/2014
WO	2007/097559 A1	8/2007

OTHER PUBLICATIONS

Search Report dated Sep. 11, 2015 for Taiwanese Application No. 104302991 with Translation.

(Continued)

Primary Examiner — Antoine D Davis
(74) *Attorney, Agent, or Firm* — Sterne, Kessler, Goldstein & Fox P.L.L.C.

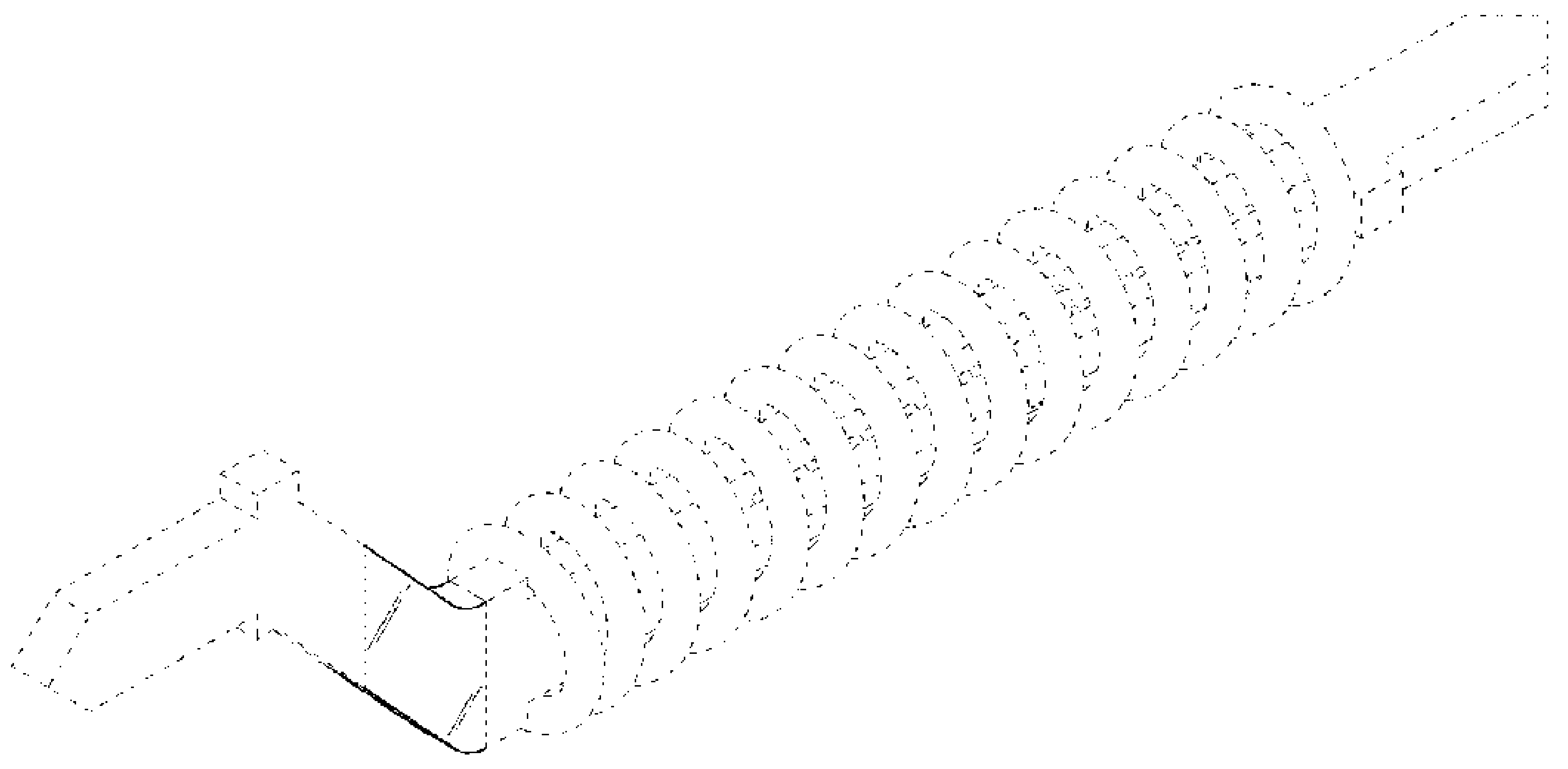
(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. **1** is a top front perspective view of a probe pin showing our new design;
FIG. **2** is a front view thereof;
FIG. **3** is a rear view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a right side view thereof;
FIG. **6** is a top view thereof; and,
FIG. **7** is a bottom view thereof.
The dashed broken lines in the figures show portions of the probe pin that form no part of the claimed design.
The dot-dash broken lines in the figures show boundaries of the claimed design.
The shade lines in the figures show contour and not surface ornamentation.

1 Claim, 4 Drawing Sheets



(56) **References Cited**

U.S. PATENT DOCUMENTS

D749,968	S *	2/2016	Huang	D10/77
D750,987	S *	3/2016	Huang	D10/80
9,322,846	B2 *	4/2016	Sakai	G01R 1/06716

OTHER PUBLICATIONS

U.S. Appl. No. 29/528,956, filed Jun. 2, 2015; Teranishi et al.

U.S. Appl. No. 29/528,958, filed Jun. 2, 2015; Teranishi et al.

Korean Office Action issued in KR Appl. No. 30-2015-0027089.

* cited by examiner

FIG. 1

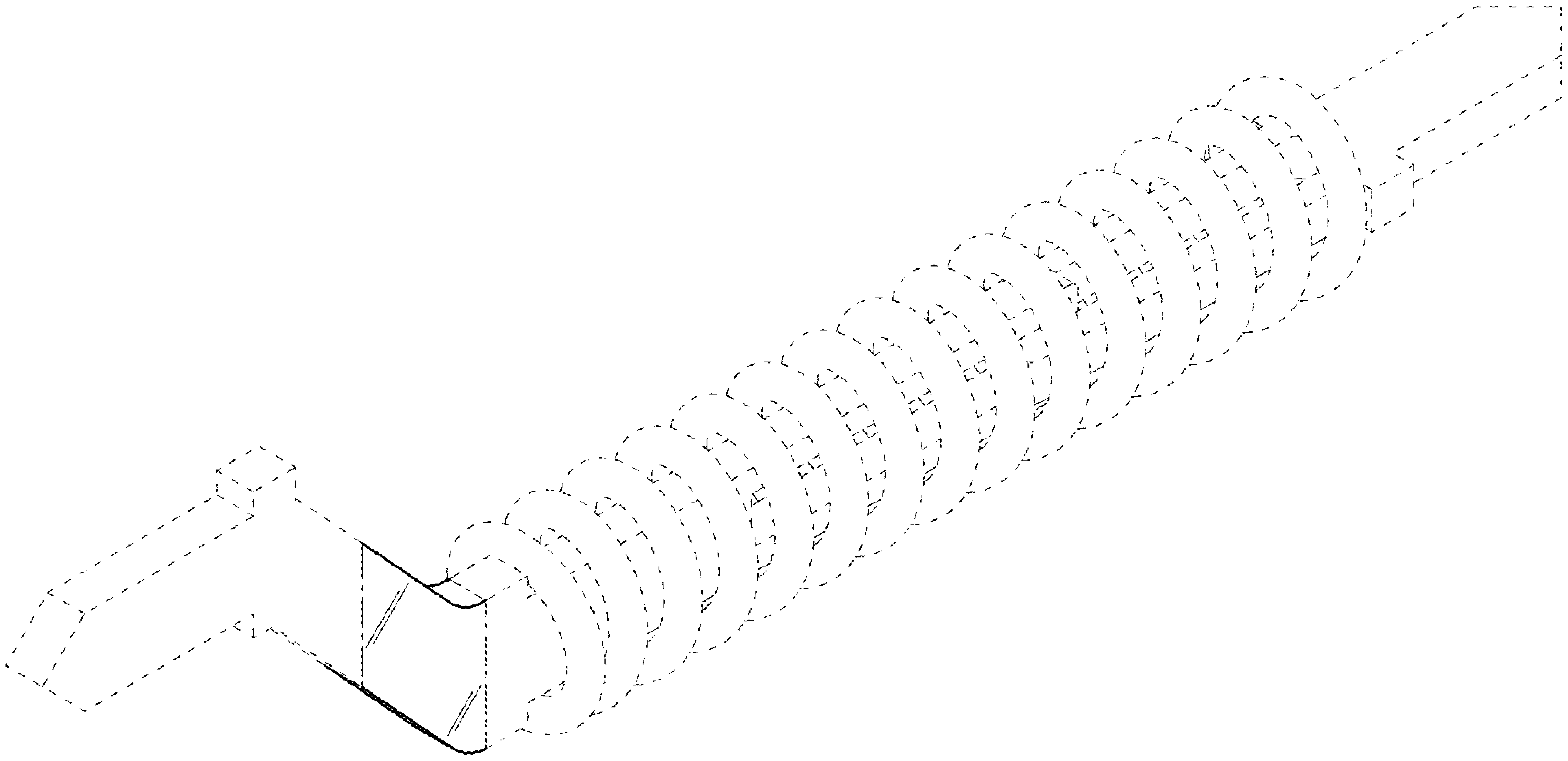


FIG. 2

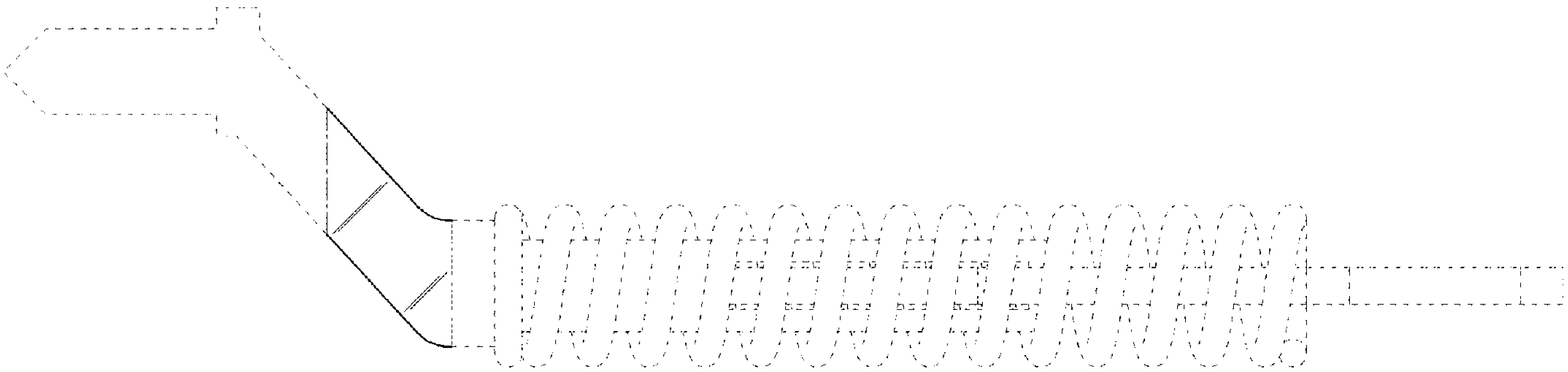


FIG. 3

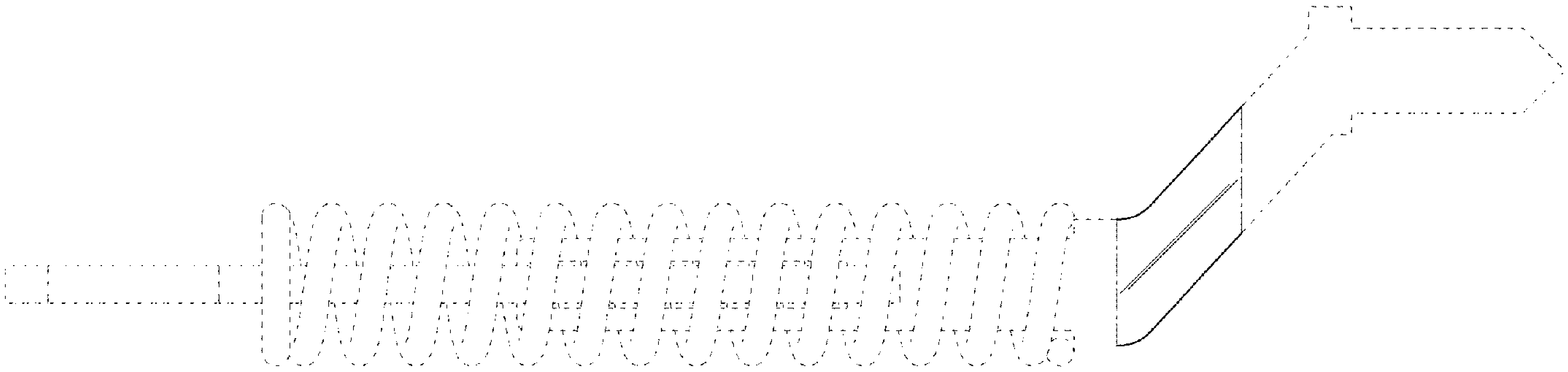


FIG. 4

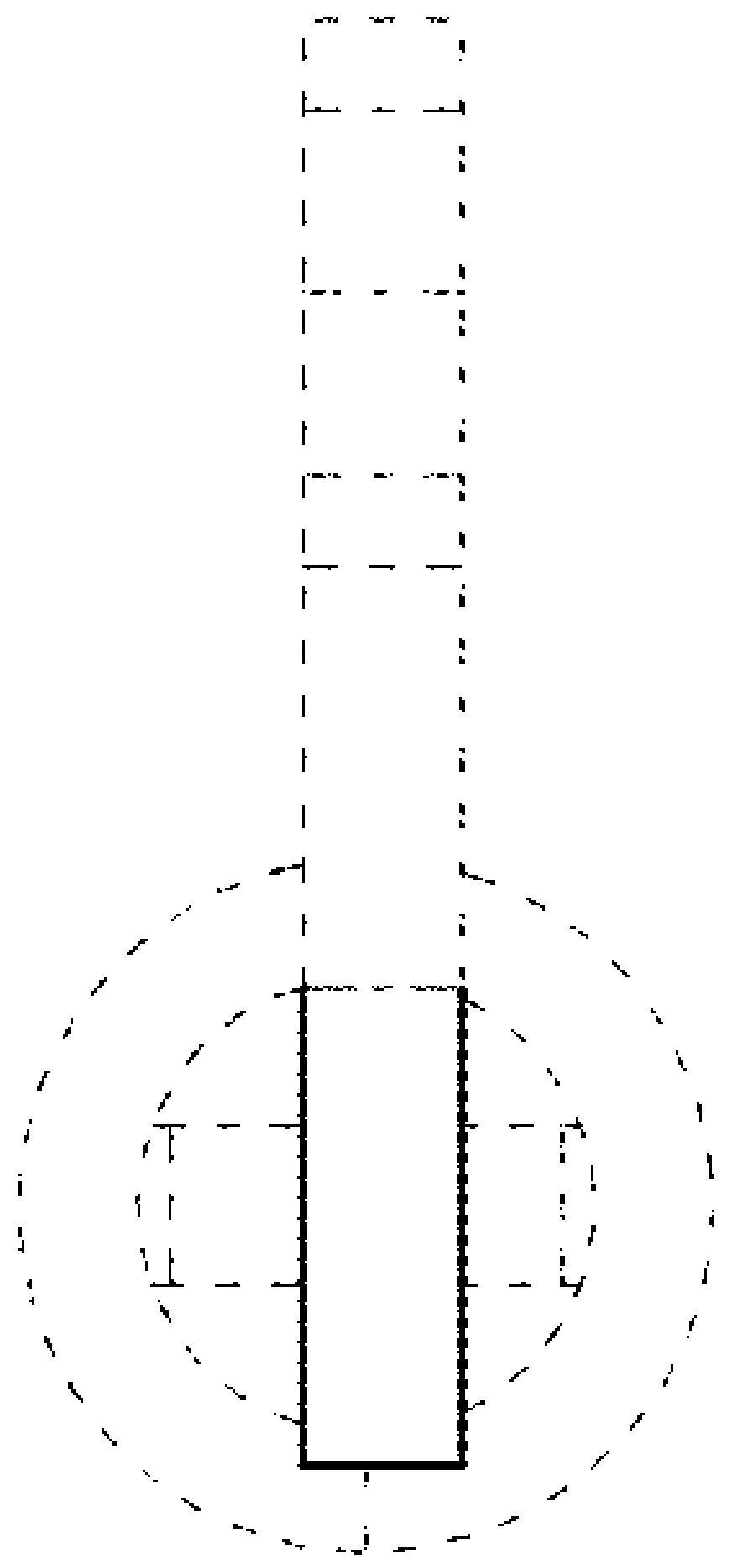
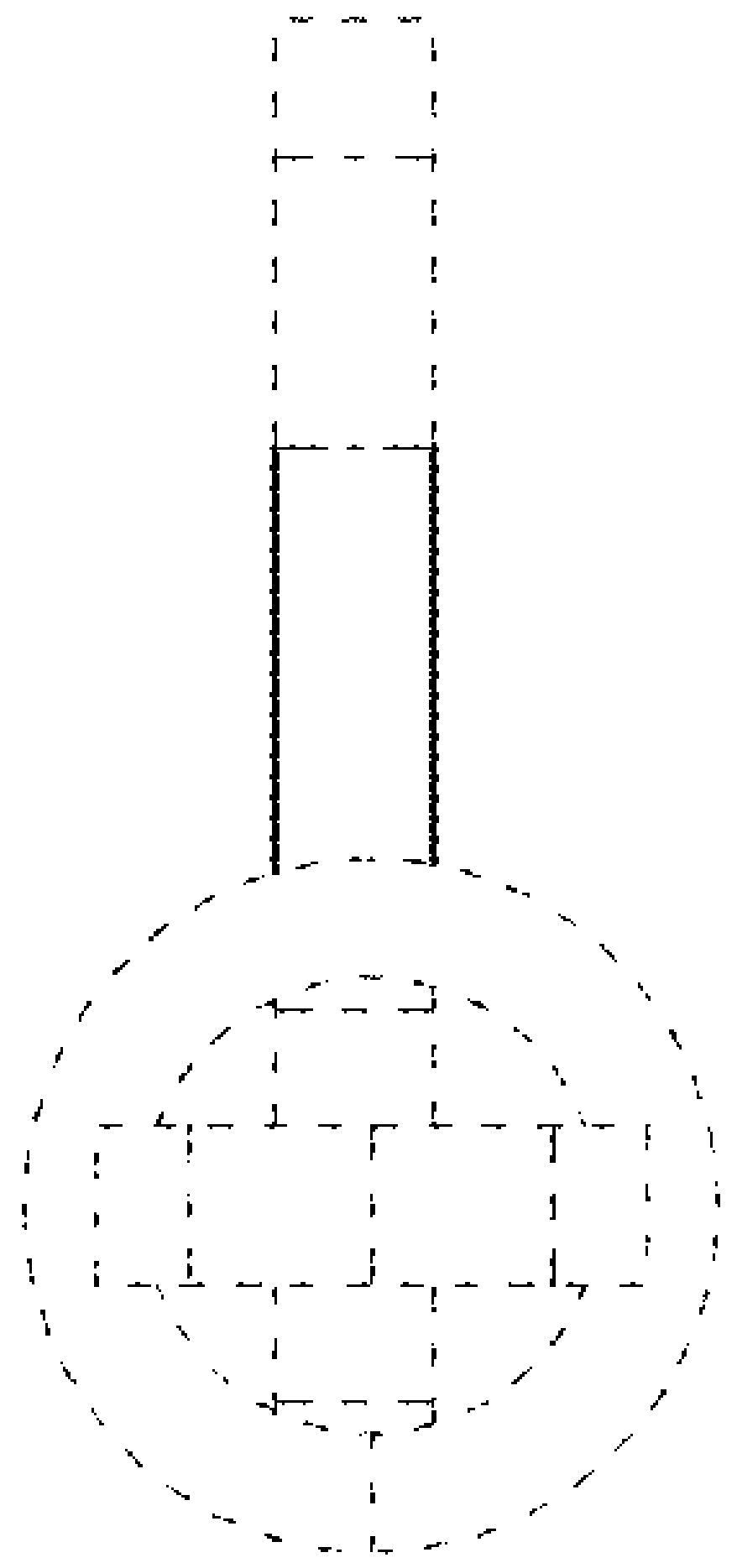


FIG. 5



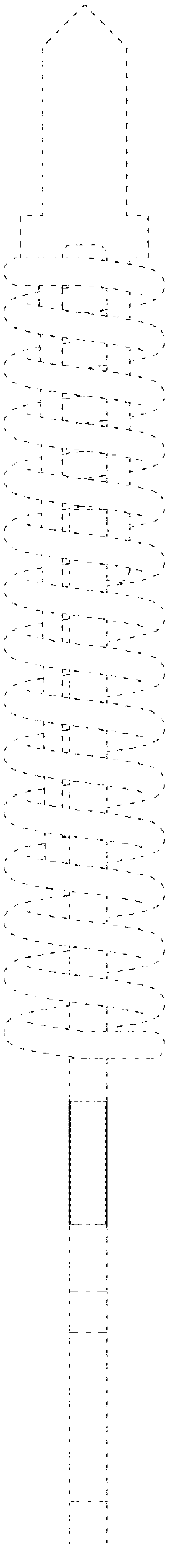


FIG. 6

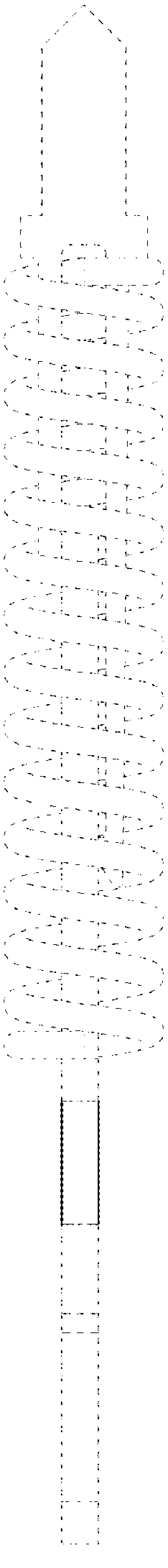


FIG. 7